## DRAFT 0.1

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## Note on estimate of efficiency

Suppose for each event one measures two variables, x and y. The events can correspond to one of two hypotheses, electron or proton (e or p). Suppose that by requiring  $y > y_{\text{cut}}$  one can achieve a very high electron purity. The goal is to estimate the electron selection efficiency of the cut on y.

Suppose one creates disjoint intervals according to the variable y, e.g.,

where for the last interval  $y_n = y_{\text{cut}}$ ; this corresponds to the final interval for which we want to know the efficiency.

Within each interval one can use the x values to determine the fractions of electrons and protons by fitting the function

$$f(x|y \in \Delta y_i, a_i) = a_i f(x|y \in \Delta y_i, e) + (1 - a_i) f(x|y \in \Delta y_i, p) .$$

$$\tag{1}$$

Here the coefficient  $a_i$  gives the fraction of electrons and it is assumed here that the pdfs  $f(x|y \in \Delta y_i, e)$  and  $f(x|y \in \Delta y_i, p)$  can be determined from Monte Carlo; for now the uncertainty in these shapes is not considered. The output of the fit is then a set of estimated values  $\hat{a}_i$  with variances  $V[\hat{a}_i]$ . As the intervals are disjoint, the estimators are uncorrelated.

The number of electrons  $N_{e,i}$  in interval *i* can be estimated as

$$\hat{N}_{\mathrm{e},i} = N_i \hat{a}_i \,, \tag{2}$$

where  $N_i$  is the total number of events in the *i*th *y* interval. The values  $N_i$  can be modeled as following a multinomial distribution with probabilities for each bin of *y* of  $p_0, p_1, \ldots, p_n$  and a total number of entries (without any cut on *y*) of  $N_{\text{tot}}$ .

The covariance matrix for the multinomial distribution is

$$\operatorname{cov}[N_i, N_j] = N_{\operatorname{tot}} p_i (\delta_{ij} - p_j) .$$
(3)

Estimates for these values can be obtained by estimating the individual probabilities using the observed numbers of events found. That is, one takes

$$\widehat{\operatorname{cov}}[N_i, N_j] = N_{\operatorname{tot}} \hat{p}_i (\delta_{ij} - \hat{p}_j) \tag{4}$$

with

$$\hat{p}_i = N_i / N_{\text{tot}} . \tag{5}$$

The desired efficiency is the expected number of electrons in y-interval n divided by the total number of electrons, i.e.,

$$\varepsilon_{\rm e} = \frac{N_{\rm tot} p_n a_n}{\sum_{i=0}^n N_{\rm tot} p_i a_i} \,. \tag{6}$$

This is estimated by using  $N_i$  to determine  $N_{\text{tot}}p_i$  and replacing the  $a_i$  with their corresponding estimators  $\hat{a}_i$ , i.e.,

$$\hat{\varepsilon}_{\rm e} = \frac{\hat{N}_{{\rm e},n}}{\sum_{i=0}^{n} \hat{N}_{{\rm e},i}} = \frac{N_n \hat{a}_n}{\sum_{i=0}^{n} N_i \hat{a}_i} \,. \tag{7}$$

As the covariance for the  $N_i$  and  $\hat{a}_i$  are available one can use error propagation to determine the corresponding variance of  $\hat{\varepsilon}_{e}$ .

In its current form, there would be no loss in simply taking two y intervals, i.e.,  $y < y_{\text{cut}}$ and  $y \ge y_{\text{cut}}$ . The formulae above still apply.

By using a larger number of y intervals, however, one could reduce the statistical error in  $\hat{\varepsilon}_{e}$  if it is possible to parameterize the dependence of the electron fraction a on the variable y. That is, suppose one had a function  $a(y; \theta)$  for some set of parameters  $\theta = (\theta_1, \ldots, \theta_m)$ , where we assume that the number of parameters m is less than the number of y intervals (n+1). Then one could carry out a standard least squares fit to determine  $\theta$  by minimizing

$$\chi^{2}(\boldsymbol{\theta}) = \sum_{i=0}^{n} \frac{(\hat{a}_{i} - a(y_{i}; \boldsymbol{\theta}))^{2}}{\sigma_{\hat{a}_{i}}^{2}} , \qquad (8)$$

where  $y_i$  could be taken as the centre of the *i*th interval. This fit would provide a covariance matrix  $V_{ij} = \operatorname{cov}[\hat{\theta}_i, \hat{\theta}_j]$ . One could then use Eq. (7) above but with  $\hat{a}_i$  replaced by  $a(y_i; \hat{\theta})$ . By using error propagation now with the covariance matrices for the  $N_i$  and the  $a(y_i, \hat{\theta})$  one can determine the variance in  $\hat{\varepsilon}_e$ .